

# NXP TEMP SENSORS (NE1617/A, SE95 and SE98)

## Temp Sensor Informations

1. Program Originator
2. Program Revision
3. Test Time

## Temp SensorTests

## Process Flows

# NXP Temp Sensors

## Temp Sensor Informations

Device Family	Device Name	Package Type	Test Type	Test Program Originator	Test Program Revision	Test Program Name	Temperature ( C )	Test Time (msec)
SE95	SE95D	SOIC-8	Trim	NXP	B	SE95TRB	80	985
	SE95DP	MSOP-8	QA	NXP	B	SE95PRB	80	615
			QA	NXP	B	SE95PHB	120	615
			QA	NXP	B	SE95PCB	0	615
SE98	SE98PW	WTSSOP-8	Trim	NXP	B	SE95PW_TRB	25	1120
			QA	NXP	B	SE95PW_PRB	25	1120
			QA	NXP	B	SE95PW_PHB	120	1120
	SE98TK	HVSON	Trim	NXP	B	SE95TK_TRB	25	1120
			QA	NXP	B	SE95TK_PRB	25	1120
			QA	NXP	B	SE95TK_PHB	80	1120
NE1617	NE1617D	QSOP-16	Trim	NXP	R	NE1617_TRR	80	1840
			PT1	NXP	R	NE1617_FRR	80	1400
			PT2	NXP	R	NE1617_FHR	115	1360
			PT3	NXP	R	NE1617_FLR	0	1360
			QA PT1	NXP	R	NE1617_PRR	80	1270
			QA PT2	NXP	R	NE1617_PHR	115	1200
			QA PT3	NXP	R	NE1617_PLR	0	1200



“To be our customers’ first and their BEST solution”

USEA

# NXP Temp Sensors

## Temp Sensor Informations

Device Family	Device Name	Package Type	Test Type	Test Program Originator	Test Program Revision	Test Program Name	Temperature ( C)	Test Time (msec)
NE1617	NE1617AD	QSOP-16	Trim	NXP	S	NE1617A_TRS	80	1850
			PT1	NXP	S	NE1617A_FRS	80	1360
			PT2	NXP	S	NE1617A_FHS	115	1320
			PT3	NXP	S	NE1617A_FLS	0	1320
			QA PT1	NXP	S	NE1617A_PRS	80	1270
			QA PT2	NXP	S	NE1617A_PHS	115	1160
			QA PT3	NXP	S	NE1617A_PLS	0	1160



“To be our customers’ first and their BEST solution”

USEA

# NXP Temp Sensor

## Temp Sensor Tests

SE95 TEST NAMES	SE98 TEST NAMES	NE1617 TEST NAMES	NE1617/A TEST NAMES
1. Continuity	1. XY Coordinates	1. Contact	1. Contact
2. Supply Current	2. Negative Continuity	2. Positive Contact	2. Positive Contact
3. Default Register	3. Positive Continuity	3. Default Trim Bits	3. Default Trim Bits
4. Default Register1	4. Supply Current	4. Trim Accuracy	4. Trim Accuracy
5. Trim OS / Temp Curve	5. Default Register	5. Supply Current	5. Supply Current
6. OTP_Readback	6. OTP Read Default	6. Check Register Deflt	6. Check Register Deflt
7. Stress_Idd	7. Frequency	7. SMBUS & ALRT Vol	7. ALBITRATE
8. Inactive_Idd	8. Temp Trim	8. Power on reset	8. SMBUS & ALRT Vol
9. Idd_Shutdown	9. Slave Address Full	9. Standby New Method	9. Power on reset
10. Slave Address	10. Stress Idd	10. Input Leakage	10. Standby New Method
11. Thyst Read Write	11. Idd Shutdown	11. Diode Leakage	11. Input Leakage
12. Tos Read Write	12. Input Leakage	12. Oscillator	12. Diode Leakage
13. Config Read Write	13. Write Read AA	13. Address Bias Current	13. Oscillator
14. VOL_SDA	14. Comparator Mode	14. Input Threshold	14. Address Bias Current
15. Power on reset	15. Interrupt Mode	15. Input Pulse Delay	15. Input Threshold
16. VOL_OS	16. Critical Mode	16. VDD, Diode Currents	16. Input Pulse Delay
17. OS Polarity	17. ALERT FCT Test	17. First Functional	17. VDD, Diode Currents
18. OS Leakage	18. CONF CTLB	18. Check Trim Bits	18. First Functional
19. Interrupt Mode	19. CONF AWLB	19. Supply Current End	19. Check Trim Bits



“To be our customers’ first and their BEST solution”

USEA

# NXP Temp Sensor

## Temp Sensor Tests

SE95 TEST NAMES	SE98 TEST NAMES	NE1617 TEST NAMES	NE1617/A TEST NAMES
20. Frequency	20. UVL	20. Correlation Factor	20. Supply Current End
	21. Threshold Voltage		21. Correlation Factor
	23. IOL_Event		
	24. IOL_SDA		
	25. OTP Readback		

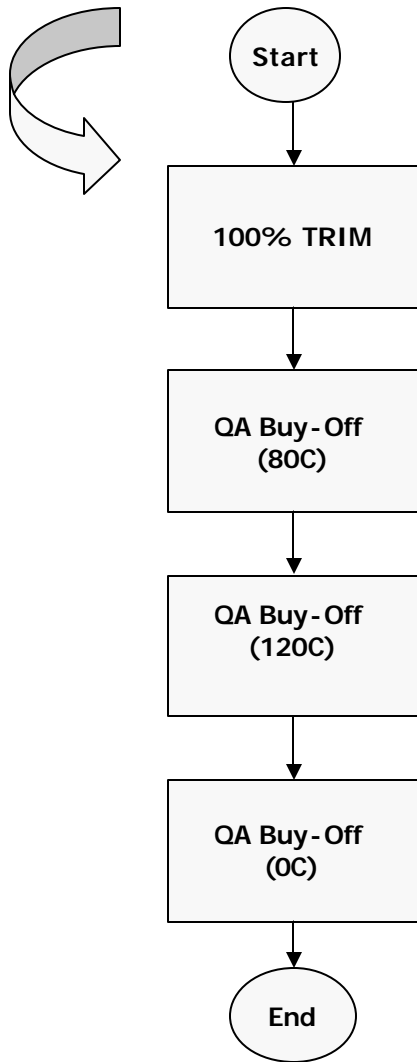


“To be our customers’ first and their BEST solution”

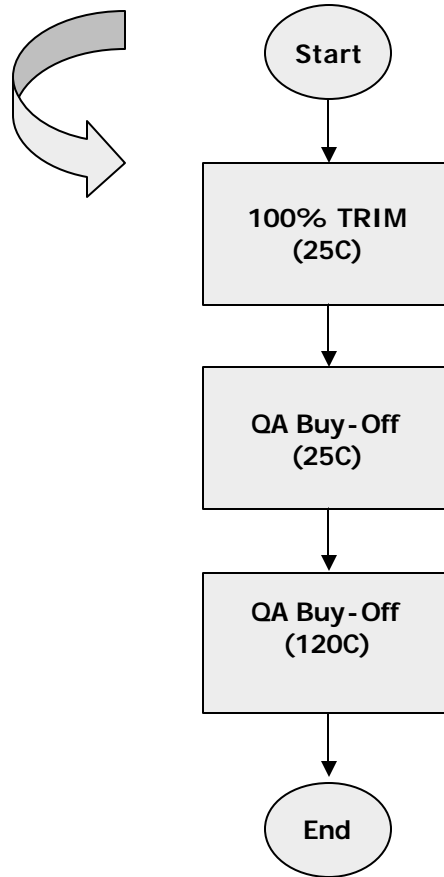
**USEA**

# NXP Temp Sensors

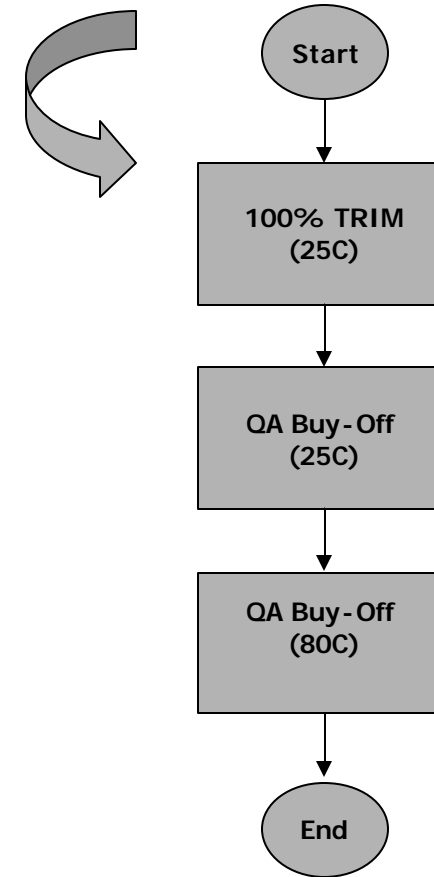
## SE95 PROCESS FLOW



## SE98PW PROCESS FLOW



## SE98TK PROCESS FLOW



QA Buy-Off on these devices on are done on every subplot (TL lot).

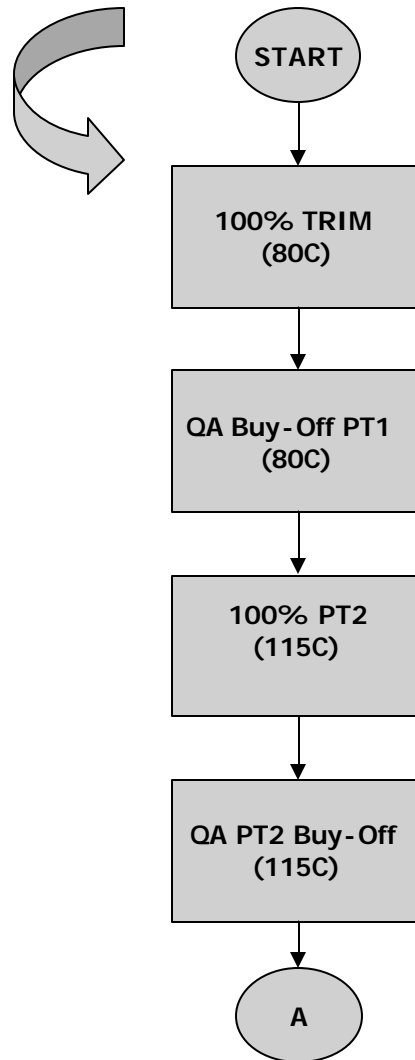


“To be our customers’ first and their BEST solution”

USEA

# NXP Temp Sensors

## NE1617/A PROCESS FLOW



QA Buy-Off of NE1617/A devices on three temperatures are done once per wafer lot only.

# NXP Temp Sensors

## NE1617/A PROCESS FLOW

